PROCEEDINGS OF SPIE

Dimensional Optical Metrology and Inspection for Practical Applications V

Kevin G. Harding Song Zhang Editors

20 April 2016
Baltimore, Maryland, United States

Sponsored and Published by SPIE

Volume 9868

Proceedings of SPIE 0277-786X, V. 9868

SPIE is an international society advancing an interdisciplinary approach to the science and application of light.

Dimensional Optical Metrology and Inspection for Practical Applications V, edited by Kevin G. Harding, Song Zhang, Proc. of SPIE Vol. 9868, 986801 © 2016 SPIE · CCC code: 0277-786X/16/\$18 · doi: 10.1117/12.2244097

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Author(s), "Title of Paper," in *Dimensional Optical Metrology and Inspection for Practical Applications V*, edited by Kevin G. Harding, Song Zhang, Proceedings of SPIE Vol. 9868 (SPIE, Bellingham, WA, 2016) Six-digit Article CID Number.

ISSN: 0277-786X

ISSN: 1996-756X (electronic) ISBN: 9781510601093

Published by

SPIE

P.O. Box 10, Bellingham, Washington 98227-0010 USA Telephone +1 360 676 3290 (Pacific Time) · Fax +1 360 647 1445 SPIE.org

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Printed in the United States of America.

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Contents

V	Authors	
V	AUIIIUIS	

vii Conference Committee

SESSION 1	OPTICAL METROLOGY ANALYSIS
9868 02	Detailed analysis of an optimized FPP-based 3D imaging system [9868-1]
9868 03	A comparative study on 3D range data compression methods [9868-2]
9868 04	A guide to properly select the defocusing distance for accurate solution of transport of intensity equation while testing aspheric surfaces [9868-3]
9868 05	ISO 10360 verification tests applied to CMMs equipped with a laser line scanner [9868-5]
9868 06	Effects of light wavelength and coherence in structured light sensors [9868-6]
SESSION 2	OPTICAL METROLOGY APPLICATIONS
9868 09	DeSCJOB: the deep space cam joined observation bot [9868-9]
9868 0A	An algorithm to estimate building heights from Google street-view imagery using single view metrology across a representational state transfer system [9868-10]
9868 OB	Design of an aid to visual inspection workstation [9868-11]
9868 OC	Non-destructive 3D shape measurement of transparent and black objects with thermal fringes [9868-12]
SESSION 3	OPTICAL METROLOGY METHODS
9868 OD	Multi-focus, high resolution inspection system for extended range applications [9868-13]
9868 OE	High-contrast 3D surface measurement without changing camera exposures [9868-14]
9868 OF	GOBO projection-based high-speed three-dimensional shape measurement [9868-15]
9868 OG	Computed tomography: a powerful imaging technique in the fields of dimensional metrology and quality control [9868-16]
9868 OH	SLM-based tomography of phase objects using single-shot transport of intensity technique [9868-17]
9868 01	High contrast imaging through adaptive transmittance control in the focal plane [9868-18]

9868 OJ	Fiber faceplate modulation readout in Bi-material micro-cantilever mirror array imaging system [9868-19]

Authors

Numbers in the index correspond to the last two digits of the six-digit citation identifier (CID) article numbering system used in Proceedings of SPIE. The first four digits reflect the volume number. Base 36 numbering is employed for the last two digits and indicates the order of articles within the volume. Numbers start with 00, 01, 02, 03, 04, 05, 06, 07, 08, 09, 0A, 0B...0Z, followed by 10-1Z, 20-2Z, etc.

Amiri, Javad, 04 Arguello, Henry, 0A Bell, Tyler, 03 Boeckmans, Bart, 05, 0G Brahm, Anika, 0C Darudi, Ahmad, 04, 0H Dewulf, Wim, 05, 0G Dhadwal, Harbans S., Ol Díaz, Elkin, 0A Dietrich, Patrick, OC, OF Dong, Liquan, 0J Duong, Kiet, 02 Feng, Dake, 01 Han, Jie, 06 Harding, Kevin G., 06, 0B, 0D Heist, Stefan, OC, OF Hirsch, Michael, 09 Hui, Mei, 0J Jiang, Chufan, 0E Kruth, Jean-Pierre, 05, 0G Kühmstedt, Peter, OC, OF Leake, Skye, 09 Liu, Ming, 0J Liu, Xiaohua, 0J Lutzke, Peter, OF McGuire, Thomas, 09 Moradi, Ali Reza, 04 Nehmetallah, Georges, 02, 04, 0H Nguyen, Thanh C., 02, 0H Notni, Gunther, 0C, 0F Parsons, Michael, 09 Probst, Gabriel, 05, 0G Ramamurthy, Rajesh, 06 Rastegar, Jahangir, Ol Rößler, Conrad, 0C Schmidt, Ingo, OF Soltani, Peyman, 04, 0H Straub, Jeremy, 09 Tait, Robert, OB Thai, Anh, 02 Tran, Dat, 02, 0H Xia, Zhengzheng, 0J Yang, Dongmin, 06 Zhai, Zirong, 06 Zhang, M., 05

Zhang, Song, 03, 0E Zhao, Yuejin, 0J

Proc. of SPIE Vol. 9868 986801-6

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